

## LOW VOLTAGE CMOS DUAL D-TYPE FLIP FLOP WITH 5V TOLERANT INPUTS

PRELIMINARY DATA

- 5V TOLERANT INPUTS
- HIGH SPEED:  
 $f_{MAX} = 150$  MHz (MAX.) at  $V_{CC} = 3V$
- POWER-DOWN PROTECTION ON INPUTS AND OUTPUTS
- SYMMETRICAL OUTPUT IMPEDANCE:  
 $|I_{OH}| = I_{OL} = 24$  mA (MIN)
- PCI BUS LEVELS GUARANTEED AT 24mA
- BALANCED PROPAGATION DELAYS:  
 $t_{PLH} \leq t_{PHL}$
- OPERATING VOLTAGE RANGE:  
 $V_{CC}$  (OPR) = 2.0V to 3.6V (1.5V Data Retention)
- PIN AND FUNCTION COMPATIBLE WITH 74 SERIES 74
- LATCH-UP PERFORMANCE EXCEEDS 500mA
- ESD PERFORMANCE:  
HBM >2000V; MM > 200V

### DESCRIPTION

The LCX74 is a low voltage CMOS OCTAL D-TYPE FLIP FLOP WITH PRESET AND CLEAR NON INVERTING fabricated with sub-micron silicon gate and double-layer metal wiring C<sup>2</sup>MOS technology. It is ideal for low power and high speed 3.3V applications; it can be interfaced to



5V signal environment for inputs.

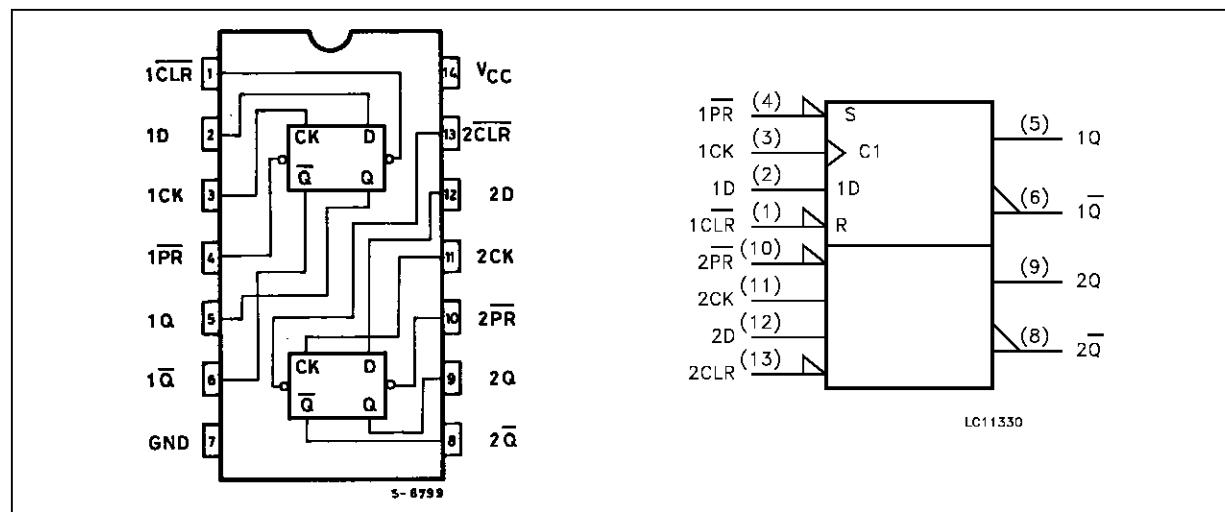
A signal on the D INPUT is transferred to the Q OUTPUT during the positive going transition of the clock pulse.

CLEAR and PRESET are independent of the clock and accomplished by a low setting on the appropriate input.

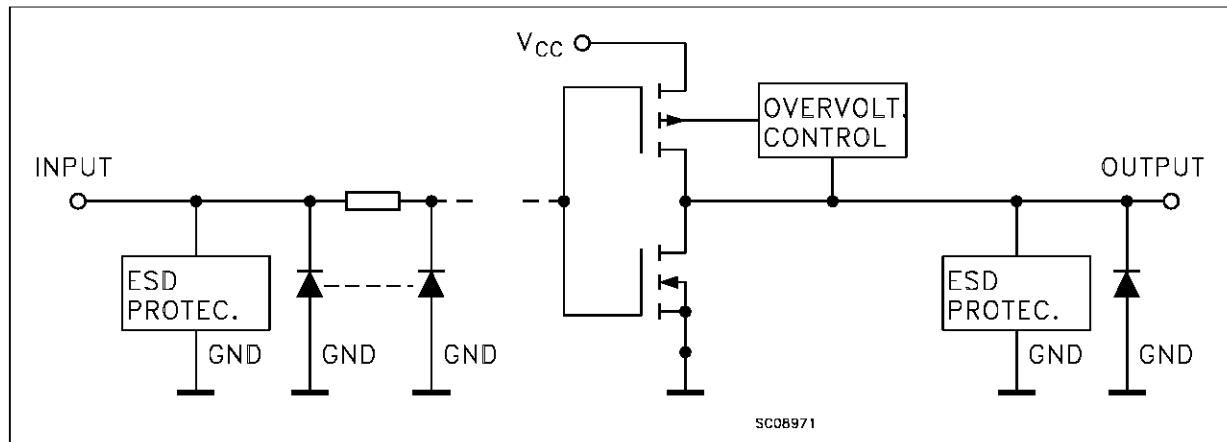
It has same speed performance at 3.3V than 5V, AC/ACT family, combined with a lower power consumption.

All inputs and outputs are equipped with protection circuits against static discharge, giving them 2KV ESD immunity and transient excess voltage.

### PIN CONNECTION AND IEC LOGIC SYMBOLS



## INPUT AND OUTPUT EQUIVALENT CIRCUIT



## PIN DESCRIPTION

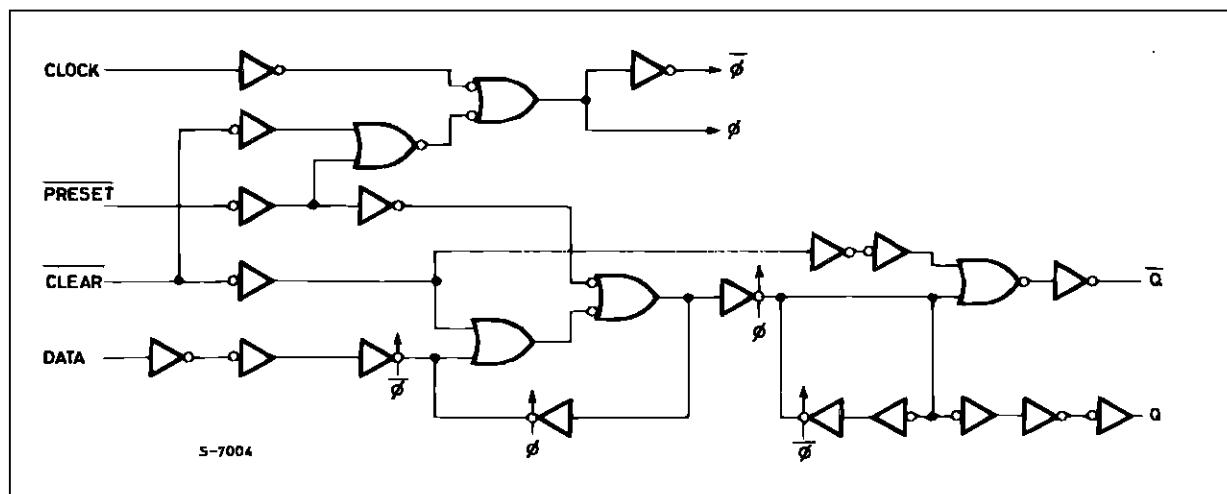
PIN No	SYMBOL	NAME AND FUNCTION
1, 13	1CLR, 2CLR	Asynchronous Reset - Direct Input
2, 12	1D, 2D	Data Inputs
3, 11	1CK, 2CK	Clock Input (LOW-to-HIGH, Edge-Triggered)
4, 10	1PR, 2PR	Asynchronous Set - Direct Input
5, 9	1Q, 2Q	True Flip-Flop Outputs
6, 8	1Q̄, 2Q̄	Complement Flip-Flop Outputs
7	GND	Ground (0V)
14	V <sub>CC</sub>	Positive Supply Voltage

## TRUTH TABLE

INPUTS				OUTPUTS		FUNCTION
CLR	PR	D	CK	Q	Q̄	
L	H	X	X	L	H	CLEAR
H	L	X	X	H	L	PRESET
L	L	X	X	H	H	
H	H	L	⊟	L	H	
H	H	H	⊟	H	L	
H	H	X	⊟	Q <sub>n</sub>	Q̄ <sub>n</sub>	NO CHANGE

X: Don't Care

## LOGIC DIAGRAMS



This logic diagram has not been used to estimate propagation delays

**ABSOLUTE MAXIMUM RATINGS**

<b>Symbol</b>	<b>Parameter</b>	<b>Value</b>	<b>Unit</b>
V <sub>CC</sub>	Supply Voltage	-0.5 to + 7.0	V
V <sub>I</sub>	DC Input Voltage	-0.5 to + 7.0	V
V <sub>O</sub>	DC Output Voltage (V <sub>CC</sub> =0V)	-0.5 to + 7.0	V
V <sub>O</sub>	DC Output Voltage (High or Low State) (note1)	-0.5 to V <sub>CC</sub> + 0.5	V
I <sub>IK</sub>	DC Input Diode Current	- 50	mA
I <sub>OK</sub>	DC Output Diode Current (note2)	± 50	mA
I <sub>O</sub>	DC Output Source/Sink Current	± 50	mA
I <sub>CC</sub>	DC Supply Current per Supply Pin	± 100	mA
I <sub>GND</sub>	DC Ground Current per Supply Pin	± 100	mA
T <sub>STG</sub>	Storage Temperature	-65 to +150	°C
T <sub>L</sub>	Lead Temperature (10 sec)	300	°C

Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these condition is not implied.

1) Io absolute maximum rating must be observed

2) V<sub>O</sub> < GND, V<sub>O</sub> > V<sub>CC</sub>

**RECOMMENDED OPERATING CONDITIONS**

<b>Symbol</b>	<b>Parameter</b>	<b>Value</b>	<b>Unit</b>
V <sub>CC</sub>	Supply Voltage (note 1)	2.0 to 3.6	V
V <sub>I</sub>	Input Voltage	0 to 5.5	V
V <sub>O</sub>	Output Voltage (V <sub>CC</sub> =0V)	0 to 5.5	V
V <sub>O</sub>	Output Voltage (High or Low State)	0 to V <sub>CC</sub>	V
I <sub>OH</sub> , I <sub>OL</sub>	High or Low Level Output Current (V <sub>CC</sub> = 3.0 to 3.6V)	± 24	mA
I <sub>OH</sub> , I <sub>OL</sub>	High or Low Level Output Current (V <sub>CC</sub> = 2.7 to 3.0V)	± 12	mA
T <sub>OP</sub>	Operating Temperature:	-40 to +85	°C
dt/dv	Input Transition Rise or Fall Rate (V <sub>CC</sub> = 3.0V) (note 2)	0 to 10	ns/V

1) Truth Table guaranteed: 1.5V to 3.6V

2) V<sub>IN</sub> from 0.8V to 2.0V

## 74LCX74

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### DC SPECIFICATIONS

Symbol	Parameter	Test Conditions		Value		Unit	
		V <sub>CC</sub> (V)		-40 to 85 °C			
				Min.	Max.		
V <sub>IH</sub>	High Level Input Voltage	2.7 to 3.6		2.0		V	
V <sub>IL</sub>	Low Level Input Voltage				0.8	V	
V <sub>OH</sub>	High Level Output Voltage	2.7 to 3.6	V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>O</sub> =-100 μA	V <sub>CC</sub> -0.2	V	
		2.7		I <sub>O</sub> =-12 mA	2.2		
		3.0		I <sub>O</sub> =-18 mA	2.4		
				I <sub>O</sub> =-24 mA	2.2		
V <sub>OL</sub>	Low Level Output Voltage	2.7 to 3.6	V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>O</sub> =100 μA	0.2	V	
		2.7		I <sub>O</sub> =12 mA	0.4		
		3.0		I <sub>O</sub> =16 mA	0.4		
		3.0		I <sub>O</sub> =24 mA	0.55		
I <sub>I</sub>	Input Leakage Current	2.7 to 3.6	V <sub>I</sub> = 0 to 5.5 V		±5	μA	
I <sub>off</sub>	Power Off Leakage Current	0	V <sub>I</sub> or V <sub>O</sub> = 5.5V		100	μA	
I <sub>CC</sub>	Quiescent Supply Current	2.7 to 3.6	V <sub>I</sub> = V <sub>CC</sub> or GND		10	μA	
			V <sub>I</sub> or V <sub>O</sub> = 3.6 to 5.5V		±10		
ΔI <sub>CC</sub>	ICC incr. per input	2.7 to 3.6	V <sub>IH</sub> = V <sub>CC</sub> -0.6V		500	μA	

### DYNAMIC SWITCHING CHARACTERISTICS

Symbol	Parameter	Test Conditions		Value			Unit	
		V <sub>CC</sub> (V)		T <sub>A</sub> = 25 °C				
				Min.	Typ.	Max.		
V <sub>OLP</sub>	Dynamic Low Voltage Quiet Output (note 1)	3.3	C <sub>L</sub> = 50 pF V <sub>IL</sub> = 0 V V <sub>IH</sub> = 3.3V	0.8			V	
				-0.8				

1) Number of outputs defined as "n". Measured with "n-1" outputs switching from HIGH to LOW or LOW to HIGH. The remaining output is measured in the LOW state.

**AC ELECTRICAL CHARACTERISTICS (C<sub>L</sub> = 50 pF, R<sub>L</sub> = 500 Ω, Input t<sub>r</sub> = t<sub>f</sub> = 2.5 ns)**

Symbol	Parameter	Test Condition		Value		Unit	
		V <sub>CC</sub> (V)	Waveform	-40 to 85 °C			
				Min.	Max.		
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay Time CK to Q or $\bar{Q}$	2.7	1	1.5	8.0	ns	
		3.0 to 3.6		1.5	7.0		
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay Time PR or CLR to Q or $\bar{Q}$	2.7	1	1.5	8.0	ns	
		3.0 to 3.6		1.5	7.0		
t <sub>S</sub>	Setup Time, HIGH or LOW level Dn to CP	2.7	1	2.5		ns	
		3.0 to 3.6		2.5			
t <sub>H</sub>	Hold Time, HIGH or LOW level Dn to CP	2.7	1	1.5		ns	
		3.0 to 3.6		1.5			
t <sub>W</sub>	CP Pulse Width, HIGH or LOW, PR or CLR Pulse Width, LOW	2.7	3	3.3		ns	
		3.0 to 3.6		3.3			
t <sub>REC</sub>	Recovery Time PR or CLR to CK	2.7	1, 3	0		ns	
		3.0 to 3.6		0			
f <sub>MAX</sub>	Clock Pulse Frequency	3.0 to 3.6	1	150		MHz	
t <sub>OSLZ</sub> t <sub>OSH</sub>	Output to Output Skew Time (note 1, 2)	3.0 to 3.6			1.0	ns	

1) Skew is defined as the absolute value of the difference between the actual propagation delay for any two outputs of the same device switching in the same direction, either HIGH or LOW ( $t_{OSLZ} = |t_{PLHm} - t_{PLHn}|$ ,  $t_{OSH} = |t_{PHLm} - t_{PHLn}|$ )

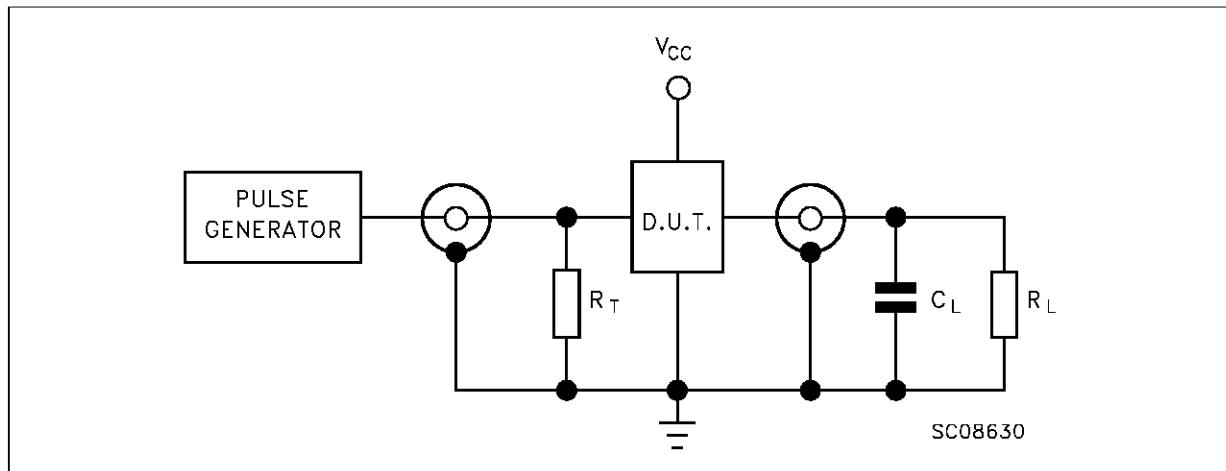
2) Parameter guaranteed by design

**CAPACITIVE CHARACTERISTICS**

Symbol	Parameter	Test Conditions		Value			Unit	
		V <sub>CC</sub> (V)		T <sub>A</sub> = 25 °C				
				Min.	Typ.	Max.		
C <sub>IN</sub>	Input Capacitance	3.3	V <sub>IN</sub> = 0 to V <sub>CC</sub>		6		pF	
C <sub>PD</sub>	Power Dissipation Capacitance (note 1)	3.3	f <sub>IN</sub> = 10MHz V <sub>IN</sub> = 0 or V <sub>CC</sub>		40		pF	

1) C<sub>PD</sub> is defined as the value of the IC's internal equivalent capacitance which is calculated from the operating current consumption without load. Average operating current can be obtained by the following equation. I<sub>CC(opr)</sub> = C<sub>PD</sub> • V<sub>CC</sub> • f<sub>IN</sub> + I<sub>CO/n</sub> (per circuit)

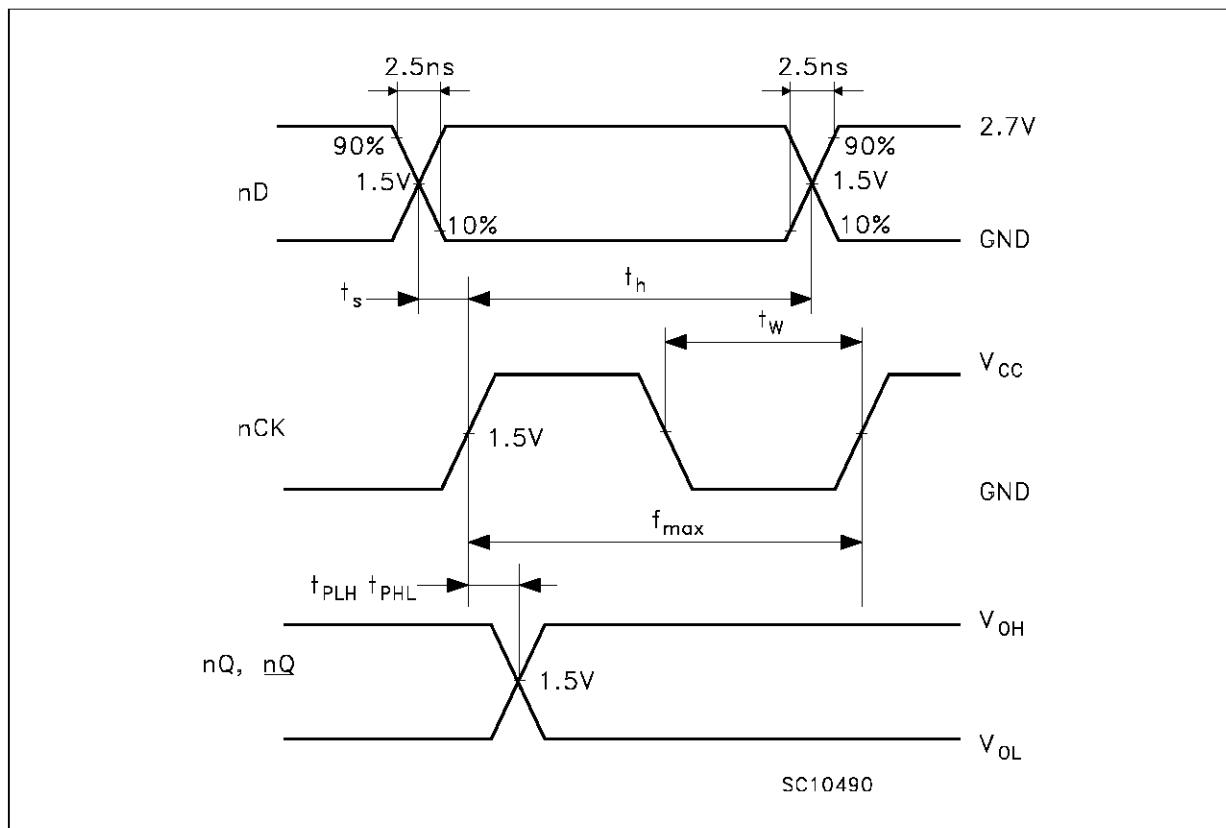
## TEST CIRCUIT



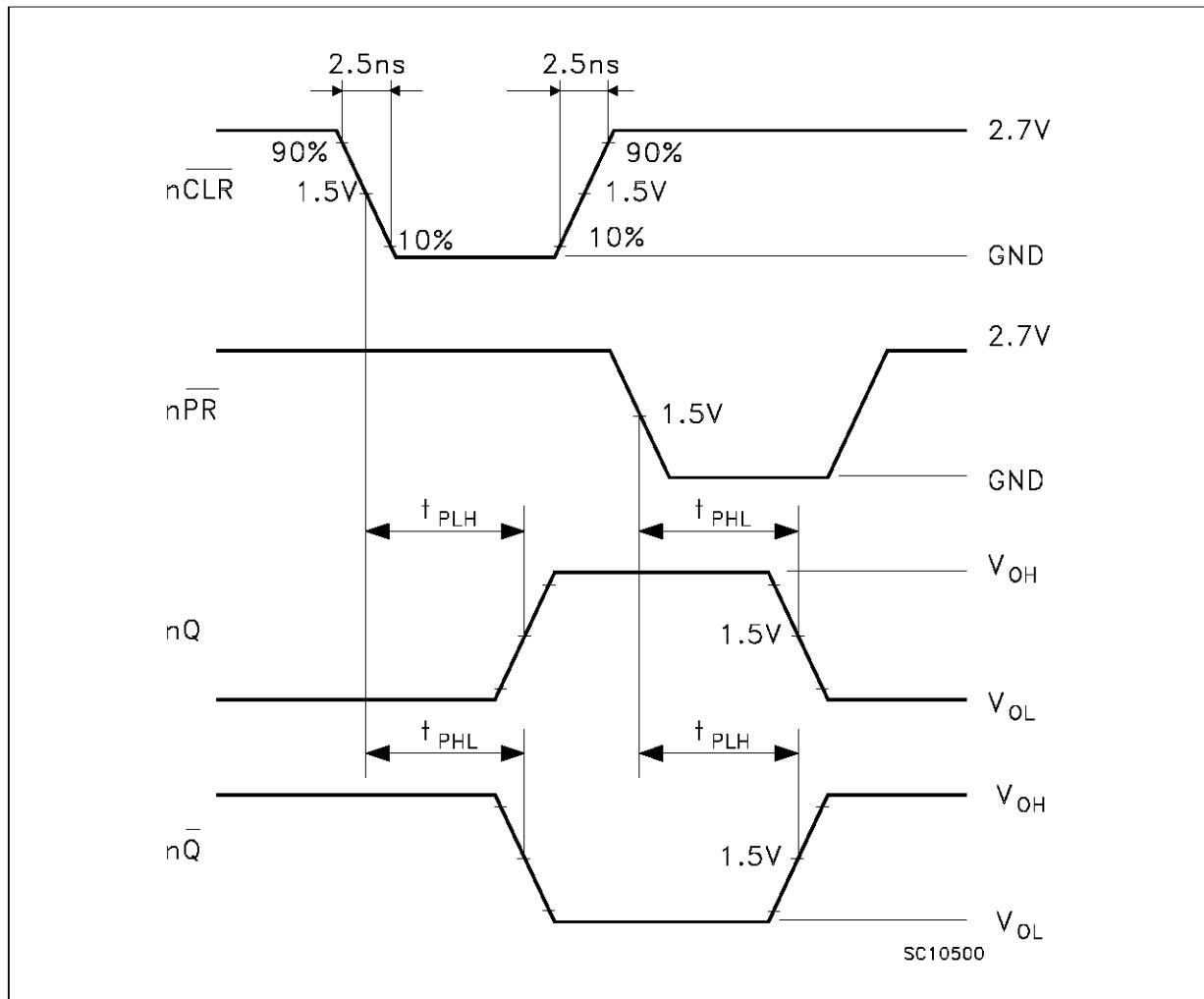
$C_L = 50 \text{ pF}$  or equivalent (includes jig and probe capacitance)

$R_L = 500\Omega$  or equivalent

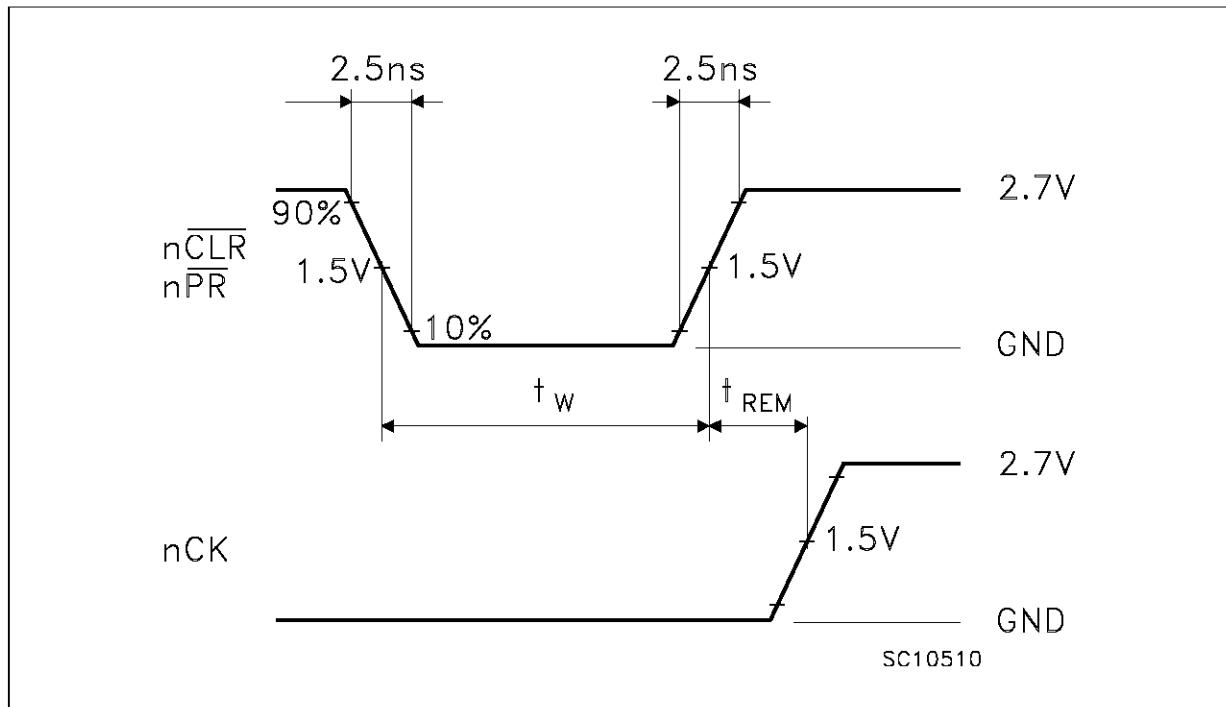
$R_T = Z_{out}$  of pulse generator (typically  $50\Omega$ )

WAVEFORM 1: PROPAGATION DELAYS, SETUP AND HOLD TIMES ( $f=1\text{MHz}$ ; 50% duty cycle)

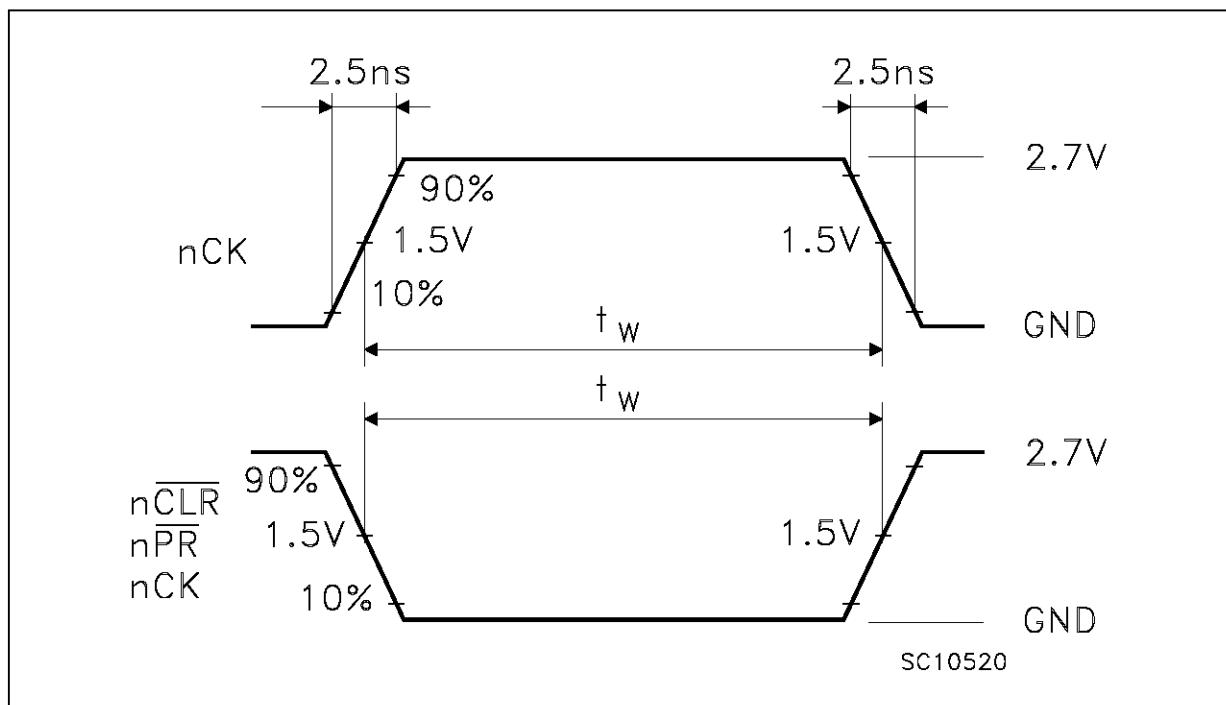
## WAVEFORM 2: PROPAGATION DELAYS (f=1MHz; 50% duty cycle)



**WAVEFORM 3: RECOVERY TIMES (f=1MHz; 50% duty cycle)**

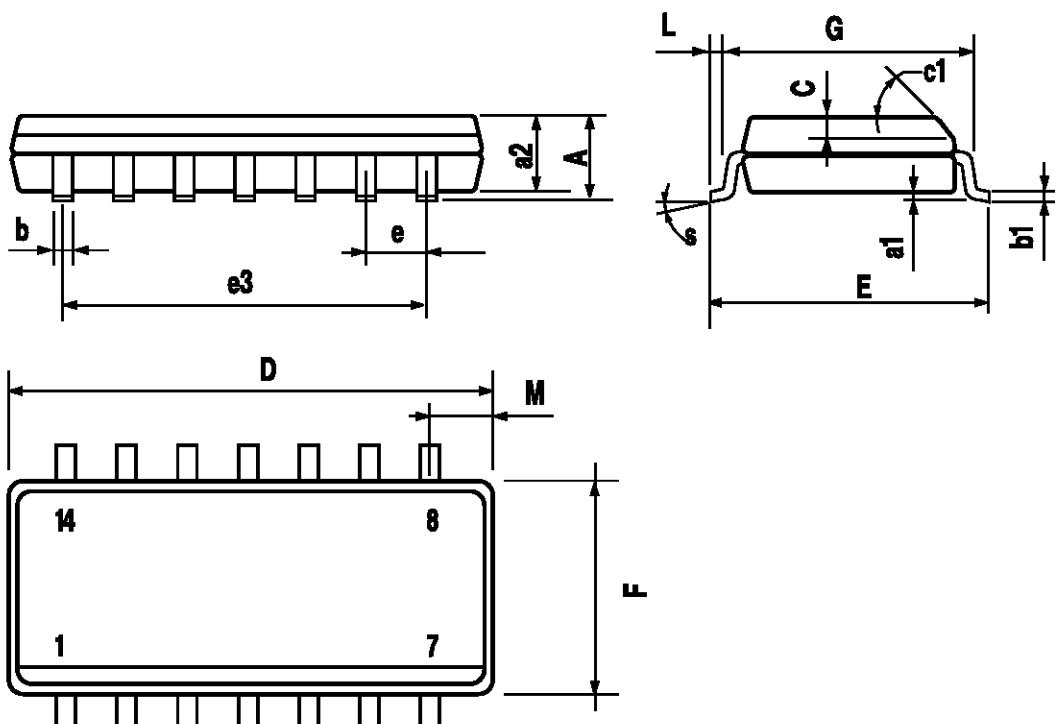


**WAVEFORM 3: PULSE WIDTH**



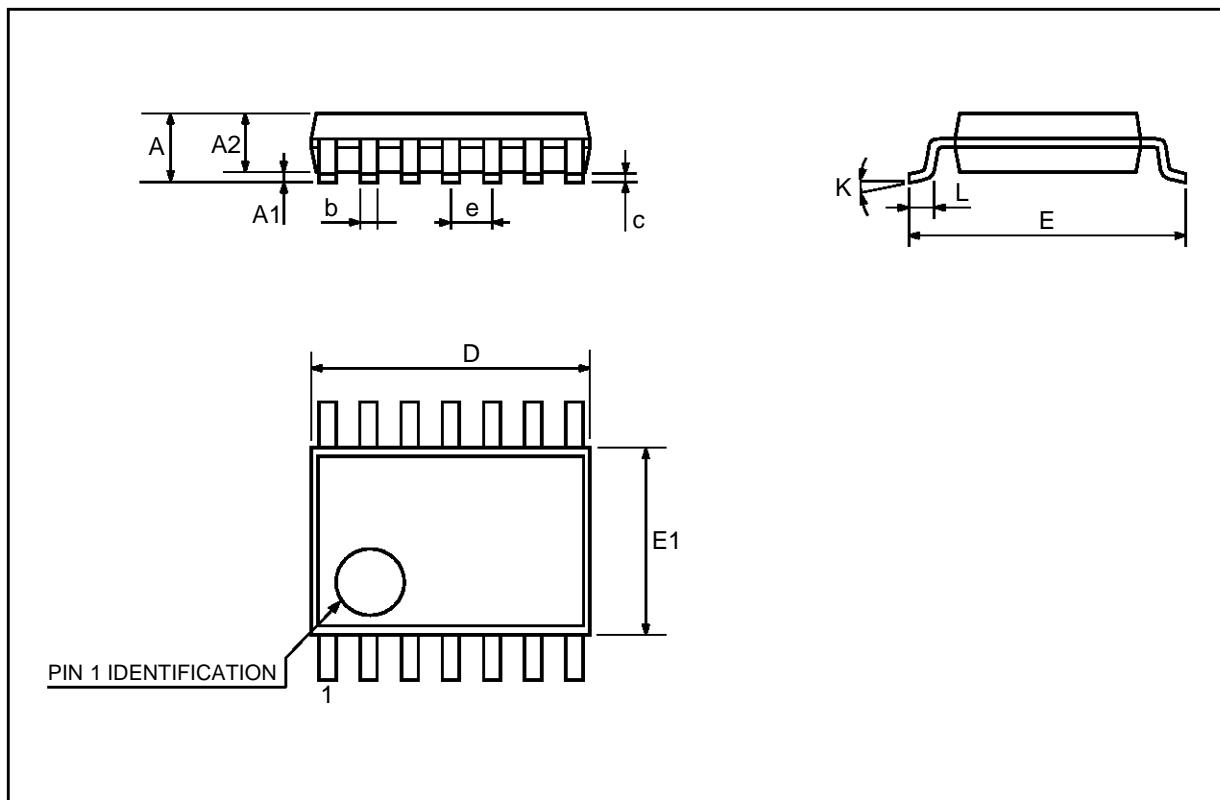
## SO14 MECHANICAL DATA

DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A			1.75			0.068
a1	0.1		0.2	0.003		0.007
a2			1.65			0.064
b	0.35		0.46	0.013		0.018
b1	0.19		0.25	0.007		0.010
C		0.5			0.019	
c1		45 (typ.)				
D	8.55		8.75	0.336		0.344
E	5.8		6.2	0.228		0.244
e		1.27			0.050	
e3		7.62			0.300	
F	3.8		4.0	0.149		0.157
G	4.6		5.3	0.181		0.208
L	0.5		1.27	0.019		0.050
M			0.68			0.026
S		8 (max.)				



## TSSOP14 MECHANICAL DATA

DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A			1.1			0.433
A1	0.05	0.10	0.15	0.002	0.004	0.006
A2	0.85	0.9	0.95	0.335	0.354	0.374
b	0.19		0.30	0.0075		0.0118
c	0.09		0.20	0.0035		0.0079
D	4.9	5	5.1	0.193	0.197	0.201
E	6.25	6.4	6.5	0.246	0.252	0.256
E1	4.3	4.4	4.48	0.169	0.173	0.176
e		0.65 BSC			0.0256 BSC	
K	0°	4°	8°	0°	4°	8°
L	0.50	0.60	0.70	0.020	0.024	0.028



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